

Notice of References Cited	Application/Control No. 10/717,464	Applicant(s)/Patent Under Reexamination SAINT ETIENNE ET AL.	
	Examiner Feben M. Haile	Art Unit 2616	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0152077	08-2003	Saint Etienne et al.	370/389
*	B	US-6,188,689	02-2001	Katsube et al.	370/389
*	C	US-6,282,669	08-2001	Imanaka et al.	714/4
*	D	US-6,799,037	09-2004	Mielke et al.	455/435.1
*	E	US-6,615,271	09-2003	Lauck et al.	709/232
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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